

Study of the formation and decay of electron-hole plasma clusters in a direct-gap semiconductor CuCl

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The master equation for the cluster-size distribution function is solved numerically to investigate the electron-hole droplet formation claimed to be discovered in the direct-gap CuCl excited by picosecond laser pulses [Nagai *et al.*, Phys. Rev. Lett. **86**, 5795 (2001); J. Lumin. **100**, 233 (2002)]. Our result shows that for the excitation in the experiment, the average number of pairs per cluster (ANPC) is only around 5.2, much smaller than that (10^6 typically for Ge) of the well studied electron-hole droplet in indirect-gap semiconductors such as Ge and Si.

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In photoexcited semiconductors, electrons and holes are generated by the photon absorption and interact with each other via the Coulomb interaction. When the exchange- and correlation-induced attractions among the high density photogenerated carriers are strong enough to overcome the fermionic repulsive pressure and to reduce the chemical potential below the exciton energy, electron-hole droplets (EHDs) appear as first order transition.¹ Investigation of the formation kinetics of EHD provides an opportunity to understand the quantum many-body effects. In semiconductor with an indirect gap and correspondingly long optical lifetimes, such as Ge and Si, EHDs have been investigated both theoretically and experimentally in great detail.² Within the coexistence regime, relatively large EHD clusters are formed and the kinetics of the EHD formation is well understood in terms of the master equation^{3,4} where the ANPC $\langle n \rangle$ is very large (for Ge $\langle n \rangle$ is about 10^6).

Unlike indirect gap semiconductors, in direct gap semiconductors the situation is very complicated because the system cannot reach quasiequilibrium during the carrier lifetime (typically in the order of 1 ns). Despite extensive experimental efforts, no decisive evidence of the EHD formation has yet been reported for a very long time.⁵ EHD formation has been predicted theoretically in polar CdS and CdSe.⁶ Also, EHD-like behavior has been observed in them experimentally in which time-resolved emission measurements are performed.^{7,8} This method has also been applied to GaAs. It reveals that electron-hole plasma created by band-to-band excitation has extremely high temperature due to the overheating caused by the reduction of band gap. Very recently, Nagai *et al.* used CuCl which has large binding energy and band gap (binding energy of 1s-Z₃ exciton E_{ex} =213 meV and band-gap energy E_g =3.396 eV) to overcome the problem. They therefore are able to study the formation of EHD in CuCl via time-resolved emission and pump-probe reflection measurements by femtosecond excitation in the mid-infrared region under resonant exciton excitation. They reported that clear EHD-like behavior in CuCl has been

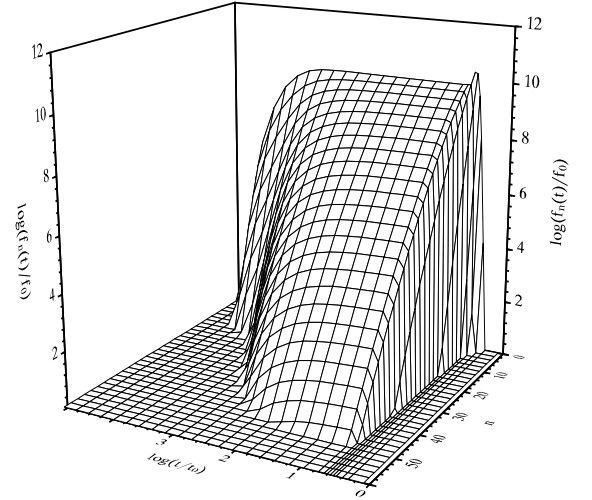


FIG. 1: Cluster concentration versus time and number of e-h pairs per cluster for CuCl at $T = 4.2$ K under Gaussian pulse excitation, $t_r=0.2$ ps, $G_0 = 6.1 \times 10^{33} \text{ cm}^{-3}\text{s}^{-1}$, and $\rho_0 = 2.0 \times 10^{20} \text{ cm}^{-3}$. $f_0 = 10^{10} \text{ cm}^{-3}$.

found.^{10,11}

However, due to the fact of the short lifetime of the carrier, one expects only small clusters can be formed and sustained. Two decades ago, Haug and Abraham performed a theoretical investigation of the EHD formation in GaAs.¹² They reported for the typical picosecond excitation the ANPC is at most around 2 where there should be no EHD formation can be found. In this paper we use the master equation theory developed by Haug and Abraham¹² to investigate the femtosecond excitation in CuCl in the experiments of Nagai *et al.*^{10,11} This the-

ory has been proven to be very successful in dealing with the EHD formation in indirect gap semiconductors.^{3,4} In this study, we focus on how big the ANPC can be in this material and how this number is affected by different parameters.

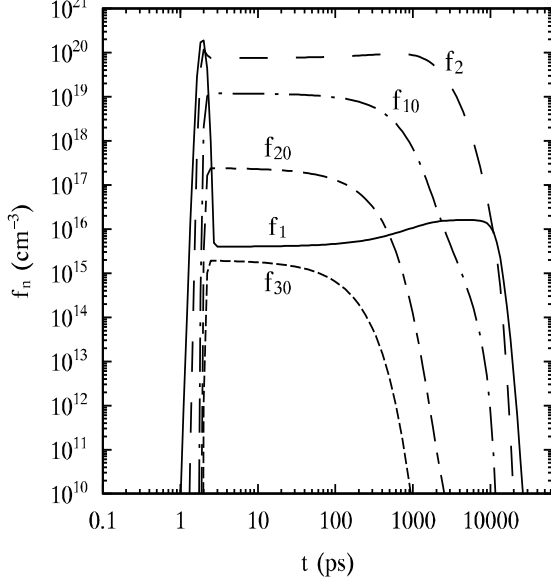


FIG. 2: Concentrations of selected clusters versus time for CuCl at T=4.2 K under Gaussian pulse excitation as in figure 1.

The concentration $f_n(t)$ to find at a given time t a cluster with n e-h pairs per unit volume is given by the following master equation equations:¹² For $n > 1$,

$$\frac{\partial f_n}{\partial t} = j_{n-1} - j_n \quad (1)$$

$$j_n = g_n f_n - l_{n+1} f_{n+1} \quad (2)$$

where j_n is the net probability current between the clusters with n and $n+1$ e-h pairs, g_n is the gain rate of a cluster with n e-h pairs and is approximated by

$$g_n = 4\pi R_n^2 v_0 f_1 \quad (3)$$

$$v_0 = \sqrt{kT/2\pi m^*} \quad (4)$$

$$n = \frac{4\pi}{3} R_n^3 \rho_0 \quad (5)$$

R_n is the radius of the cluster, v_0 is the thermal exciton velocity, ρ_0 is the liquid density. The loss rate l_n is the sum of the evaporation rate e_n and the recombination rate n/τ_n :

$$l_n = e_n + n/\tau_n. \quad (6)$$

e_n is given by the Richardson-Dushman current³

$$e_n = \gamma \left(\frac{m^* kT}{2\pi \hbar^2} \right)^{3/2} \frac{g_{n-1}}{f_1} \exp[(-\phi + c\sigma n^{-1/3})/\beta] \quad (7)$$

γ is the degeneracy of the exciton level, ϕ is the binding energy of the liquid with respect to the exciton. $c\sigma n^{-1/3}$ is the correction of the binding energy with σ denoting the surface energy of the liquid. Typically we select $\gamma = 1$. $\sigma = C\varphi\rho_0 r_0$ with $C \sim 1$, φ standing for the condensate energy per electron-hole pair and $r_0 = (3/4\pi\rho_0)^{1/3}$.¹ The change of exciton (corresponding to $n = 1$) is treated separately:

$$\frac{\partial f_1}{\partial t} = G(t) - \sum_{n=1}^{\infty} \frac{f_n}{\tau_n} - 2j_1 - \sum_{n=2}^{\infty} j_n \quad (8)$$

where $G(t)$ is the generation rate of excitons.

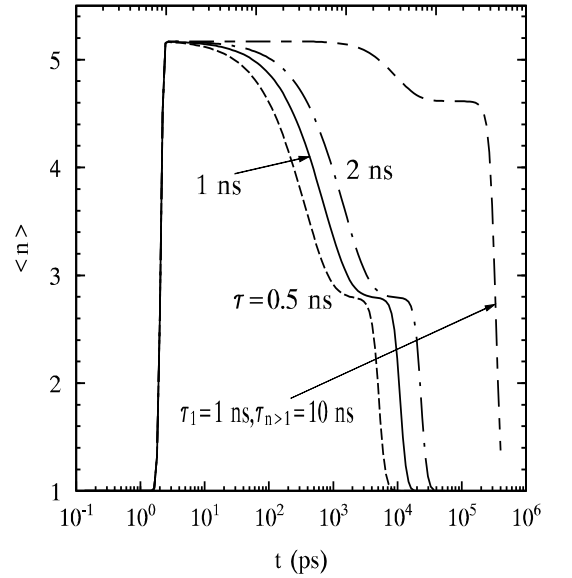


FIG. 3: ANPC versus time for CuCl at T=4.2 K under Gaussian pulse excitation. $t_r=0.2$ ps, $G_0 = 6.1 \times 10^{33} \text{ cm}^{-3}\text{s}^{-1}$, $\rho_0 = 2.0 \times 10^{20} \text{ cm}^{-3}$. Solid curve: $\tau = 1$ ns; Dashed curve: $\tau = 0.5$ ns; Dot-dashed curve: $\tau=2$ ns.

We solve above equations numerically for the example of CuCl. The parameters for CuCl at 4.2 K are $m^*=2.0m_0$ and $\phi = 5.12 \times 10^{-14} \text{ erg}$.¹³ The value of the binding energy ϕ is taken to be the biexciton binding energy which is the lower limit of the binding energy. Our computation indicates that the result is almost unchanged if one increases ϕ by one order of magnitude. We obtain ρ_0 from $r_s = \sqrt[3]{3/4\pi n a_0^3}$, where a_0 is the Bohr radius and $r_s=1.8$.¹⁰ $\sigma = 0.54 \text{ erg}\cdot\text{cm}^{-2}$. In our calculation we assume $\tau_n \equiv \tau$. According to the experiment, we

choose a Gaussian pulse:

$$G(t) = G_0 e^{-(t-t_0)^2/t_r^2} \quad (9)$$

where the pulse width $t_r = 0.2$ ps, and the peak generation rate is $G_0 = 6.1 \times 10^{33} \text{ cm}^{-3}\text{s}^{-1}$, corresponding to a excitation density of $4.3 \text{ mJ}\cdot\text{cm}^{-2}$. The main results of our calculation are plotted in Figs. 1-3.

Figure 1 shows the development of the distribution of cluster distribution. For the short pulse, the exciton concentration $f_1(t)$ rapidly reaches its maximum near the pulse center, $t_0 = 2$ ps. Then it decreases quickly due to the formation of the clusters. It is also noted from the figure that within 1 ps after the center of the pulse, clusters of all sizes reaches to their maximum values. As any cluster with size $n \geq 2$ comes from the exciton, $f_1(t)$ sharply drops 5 orders of magnitude from its peak within that period of time. After that, because of the recombination and the evaporation, almost all clusters start to decay, except for some small clusters (say $n = 1$ and 2) which increase a little bit due to the evaporation from bigger clusters. The lifetime of large cluster (say $n = 50$) is much shorter than that of the small one as the later gets compensation from the decay of the larger clusters and also the recombination rate n/τ_n is propotional to n . After 10 ns almost all cluster concentrations are below 10^{10} cm^{-3} . This can be seen more quantitatively in Fig. 2 where the concentration of some selected clusters are plotted as functions of time.

In order to see in average how large the cluster can be under the experiments by Nagai *et al.*, we plot in Fig. 3 the ANPC $\langle n \rangle$ as function of time for three different lifetimes τ . $\langle n \rangle$ can be calculated from

$$\langle n \rangle = \frac{\sum_{n=1}^{\infty} n f_n}{\sum_{n=1}^{\infty} f_n} \quad (10)$$

One notices from the figure that for the excitation in the experiment, ANPC is only 5.2, orders of magnitude smaller than the number in the EHD of indirect semiconductor such as Ge and Si. This result is consistent with the regular expectation of the excitation in the direct gap semiconductors. Moreover, if one assumes that the larger clusters are stable and therefore τ_n ($n \geq 2$) is larger than τ_1 . We demonstrate in the same figure the result when $\tau_1 = 1$ ns but $\tau_n = 10$ ns when $n \geq 2$. One finds that this does not affect the ANPC, although the metastable time is much longer. We further find that if we increase the excitation G_0 by one order of magnitude, we can only double the ANPC. These results indicate that the feature of low ANPC is very robust. These results indicate that what measured in CuCl by Nagai *et al.*^{10,11} may not come from the EHD formed from exciton gas, but instead possibly come from some bubbles of excitons in metallic liquid.¹¹

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